Search Notes

Application/Control No.	Applicant(s)/Patent unde Reexamination
10/765,729	PARKER ET AL.
Examiner	Art Unit

10/765,72 Examiner
Chen-We

Chen-Wen Jiang

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SEARCHED			
Class	Subclass	Date	Examiner
62	296		
415	220		
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(INCLUDING SE	ARCH STRATEGY	<u> </u>
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EAST Searched Inventor Searched	2/17/2006	CJ
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